

Edition 1.0 2016-03

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 2: Test procedures

Modules photovoltaïques (PV) pour applications terrestres – Qualification de la conception et homologation –

Partie 2: Procédures d'essai





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Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 2: Test procedures

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

ICS 27.160 ISBN 978-2-8322-3205-7

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# CONTENTS

| FC | REWO  | RD  | 5   |
|----|-------|---|-----|
| IN | TRODU | CTION   | 7   |
| 1  | Scop  | e and object  | 8   |
| 2  | Norm  | ative references  | 8   |
| 3  | Term  | s and definitions   | 9   |
| 4  | Test  | procedures  | .10 |
|    |       | Visual inspection (MQT 01)  |     |
|    | 4.1.1 | Purpose   |     |
|    | 4.1.2 | ·   |     |
|    | 4.1.3 |   |     |
|    | 4.2   | Maximum power determination (MQT 02)                                |     |
|    | 4.2.1 | Purpose   |     |
|    | 4.2.2 | Apparatus   | .11 |
|    | 4.2.3 | Procedure   | .11 |
|    | 4.3   | Insulation test (MQT 03)  | .11 |
|    | 4.3.1 | Purpose   | .11 |
|    | 4.3.2 | Apparatus   | .12 |
|    | 4.3.3 | Test conditions   | .12 |
|    | 4.3.4 | Procedure   | .12 |
|    | 4.3.5 | Test requirements   | .12 |
|    | 4.4   | Measurement of temperature coefficients (MQT 04)                    | .12 |
|    | 4.5   | Measurement of nominal module operating temperature (NMOT) (MQT 05) | .13 |
|    | 4.5.1 | General   | .13 |
|    | 4.5.2 | Principle   | .13 |
|    | 4.5.3 | Test procedure  | .13 |
|    | 4.6   | Performance at STC and NMOT (MQT 06)                                | .14 |
|    | 4.6.1 | Purpose   | .14 |
|    | 4.6.2 | Apparatus   | .14 |
|    | 4.6.3 | Procedure   | .14 |
|    |       | Performance at low irradiance (MQT 07)                              | .15 |
|    | 4.7.1 | Purpose   | .15 |
|    | 4.7.2 | Apparatus   | .15 |
|    | 4.7.3 | Procedure   |     |
|    | 4.8   | Outdoor exposure test (MQT 08)                                      |     |
|    | 4.8.1 | Purpose   |     |
|    | 4.8.2 | Apparatus   |     |
|    | 4.8.3 | Procedure   |     |
|    | 4.8.4 | Final measurements  |     |
|    | 4.8.5 | Requirements  |     |
|    | 4.9   | Hot-spot endurance test (MQT 09)                                    |     |
|    | 4.9.1 | Purpose   |     |
|    | 4.9.2 | Hot-spot effect   |     |
|    | 4.9.3 | Classification of cell interconnection                              |     |
|    | 4.9.4 | Apparatus   |     |
|    | 4.9.5 | Procedure   |     |
|    | 4.9.6 | Final measurements  | .27 |

| 4.9.7   | Requirements  | 2  |
|---|---|--|
| 4.10 UV   | preconditioning test (MQT 10)   | 27   |
| 4.10.1  | Purpose   | 27   |
| 4.10.2  | Apparatus   | 27   |
| 4.10.3  | Procedure   | 28   |
| 4.10.4  | Final measurements  | 28   |
| 4.10.5  | Requirements  | 28   |
| 4.11 The  | ermal cycling test (MQT 11)   | 28   |
| 4.11.1  | Purpose   | 28   |
| 4.11.2  | Apparatus   | 28   |
| 4.11.3  | Procedure   | 29   |
| 4.11.4  | Final measurements  | 29   |
| 4.11.5  | Requirements  | 30   |
| 4.12 Hur  | nidity-freeze test (MQT 12)   | 30   |
| 4.12.1  | Purpose   | 30   |
| 4.12.2  | Apparatus   | 30   |
| 4.12.3  | Procedure   | 30   |
| 4.12.4  | Final measurements  | 30   |
| 4.12.5  | Requirements  | 30   |
| 4.13 Dar  | mp heat test (MQT 13)   | 3′   |
| 4.13.1  | Purpose   | 3′   |
| 4.13.2  | Procedure   | 3′   |
| 4.13.3  | Final measurements  | 3′   |
| 4.13.4  | Requirements  | 3′   |
| 4.14 Rol  | oustness of terminations (MQT 14)   | 32   |
| 7.17 1101   | 703thess of terminations (MQ1 14)   |  |
| 4.14.1  | Purpose   |  |
|   |   | 32   |
| 4.14.1  | Purpose   | 32<br>32   |
| 4.14.1<br>4.14.2<br>4.14.3  | Purpose   | 32<br>32   |
| 4.14.1<br>4.14.2<br>4.14.3  | Purpose   | 32<br>32<br>32   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We   | Purpose  Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)   | 32<br>32<br>35   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1   | Purpose   | 32<br>32<br>35<br>35   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2   | Purpose  Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose  Apparatus   | 32<br>32<br>35<br>35   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15)  Purpose Apparatus Procedure  | 32<br>32<br>38<br>38<br>38   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4   | Purpose  Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose  Apparatus  Procedure  Requirements  | 32<br>32<br>38<br>38<br>38<br>36   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta   | Purpose  Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose  Apparatus  Procedure  Requirements  tic mechanical load test (MQT 16)   | 32<br>32<br>38<br>38<br>36<br>36   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1   | Purpose  Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose  Apparatus  Procedure  Requirements  tic mechanical load test (MQT 16)  Purpose  | 32<br>32<br>35<br>36<br>36<br>36   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15)  Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16)  Purpose Apparatus  | 32<br>32<br>35<br>35<br>35<br>36<br>36<br>36<br>36<br>36<br>37<br>37                   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15)  Purpose  Apparatus  Procedure  Requirements  tic mechanical load test (MQT 16)  Purpose  Apparatus  Procedure  Procedure  Procedure  Apparatus  Procedure  | 32<br>32<br>32<br>33<br>35<br>36<br>36<br>36<br>36<br>37<br>37<br>37<br>37             |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15)  Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16)  Purpose Apparatus Procedure Final measurements   | 32<br>32<br>35<br>36<br>36<br>36<br>37<br>37   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5   | Purpose Retention of junction box on mounting surface (MQT 14.1) Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15) Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16) Purpose Apparatus Procedure Final measurements Requirements Requirements  | 32<br>32<br>35<br>36<br>36<br>36<br>36<br>37<br>37                                     |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16)  Purpose Apparatus Procedure Final measurements Requirements Requirements I test (MQT 17)  | 32<br>32<br>35<br>36<br>36<br>36<br>37<br>37<br>37                                     |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1   | Purpose Retention of junction box on mounting surface (MQT 14.1)  Test of cord anchorage (MQT 14.2)  t leakage current test (MQT 15)  Purpose  Apparatus  Procedure  Requirements  tic mechanical load test (MQT 16)  Purpose  Apparatus  Procedure  Final measurements  Requirements  Requirements  I test (MQT 17)  Purpose   | 32<br>35<br>36<br>36<br>36<br>37<br>37<br>37<br>37                                     |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1<br>4.17.2   | Purpose Retention of junction box on mounting surface (MQT 14.1) Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15) Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16) Purpose Apparatus Procedure Final measurements Requirements I test (MQT 17) Purpose Apparatus   | 32<br>32<br>35<br>36<br>36<br>37<br>37<br>37<br>37<br>38<br>38<br>38                   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1<br>4.17.2<br>4.17.3                                 | Purpose Retention of junction box on mounting surface (MQT 14.1) Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15) Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16) Purpose Apparatus Procedure Final measurements I test (MQT 17) Purpose Apparatus Procedure Procedure Procedure Procedure Procedure Procedure  | 32<br>32<br>36<br>36<br>36<br>37<br>37<br>37<br>37<br>38<br>38<br>38                   |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1<br>4.17.2<br>4.17.3<br>4.17.4<br>4.17.5             | Purpose Retention of junction box on mounting surface (MQT 14.1) Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15) Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16) Purpose Apparatus Procedure Final measurements I test (MQT 17) Purpose Apparatus Procedure Final measurements I test (MQT 17) Purpose Apparatus Procedure Final measurements Final measurements   | 32<br>35<br>36<br>36<br>36<br>36<br>37<br>37<br>37<br>37<br>38<br>38<br>38<br>38       |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1<br>4.17.2<br>4.17.3<br>4.17.4<br>4.17.5             | Purpose Retention of junction box on mounting surface (MQT 14.1) Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15) Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16) Purpose Apparatus Procedure Final measurements Requirements I test (MQT 17) Purpose Apparatus Procedure Final measurements Requirements Requirements Procedure Final measurements Requirements Procedure Final measurements Requirements  | 32<br>32<br>36<br>36<br>37<br>37<br>37<br>37<br>37<br>38<br>38<br>38<br>38<br>38<br>38 |
| 4.14.1<br>4.14.2<br>4.14.3<br>4.15 We<br>4.15.1<br>4.15.2<br>4.15.3<br>4.15.4<br>4.16 Sta<br>4.16.1<br>4.16.2<br>4.16.3<br>4.16.4<br>4.16.5<br>4.17 Hai<br>4.17.1<br>4.17.2<br>4.17.3<br>4.17.4<br>4.17.5<br>4.18 Byr | Purpose Retention of junction box on mounting surface (MQT 14.1).  Test of cord anchorage (MQT 14.2) t leakage current test (MQT 15).  Purpose Apparatus Procedure Requirements tic mechanical load test (MQT 16)  Purpose Apparatus Procedure Final measurements I test (MQT 17).  Purpose Apparatus Procedure Final measurements Requirements I test (MQT 17)  Purpose Apparatus Procedure Final measurements Requirements Apparatus Procedure Final measurements Requirements Apparatus Procedure Final measurements Requirements Requirements | 323235363637373737383838383838   |

| 4.19.1          | General   | 43 |
|-----------------|---|----|
| 4.19.2          | Criterion definition for stabilization  | 43 |
| 4.19.3          | Light induced stabilization procedures  | 44 |
| 4.19.4          | Other stabilization procedures  | 45 |
| 4.19.5          | Initial stabilization (MQT 19.1)  | 45 |
| 4.19.6          | Final stabilization (MQT 19.2)  | 45 |
| Figure 1 – Cas  | e S, series connection with optional bypass diode   | 17 |
| Figure 2 – Cas  | e PS, parallel-series connection with optional bypass diode   | 18 |
| Figure 3 – Cas  | e SP, series-parallel connection with optional bypass diode   | 18 |
| Figure 4 – Mod  | dule I-V characteristics with different cells totally shadowed  | 20 |
| Figure 5 – Mod  | dule I-V characteristics with the test cell shadowed at different levels                                    | 21 |
| Figure 6 – Hot- | -spot effect in a MLI thin-film module with serially connected cells  | 22 |
|                 | dule I-V characteristics with different cells totally shadowed where the includes bypass diodes             | 24 |
|                 | dule I-V characteristics with the test cell shadowed at different levels lule design includes bypass diodes | 25 |
| Figure 9 – The  | rmal cycling test – Temperature and applied current profile   | 29 |
| Figure 10 – Hu  | ımidity-freeze cycle – Temperature and humidity profile   | 31 |
| Figure 11 – Ty  | pical arrangement for the cord anchorage pull test for component testing                                    | 34 |
| Figure 12 – Ty  | pical arrangement for torsion test  | 34 |
| Figure 13 – Ha  | iil-test equipment  | 38 |
|                 | til test impact locations: top for wafer/cell based technologies, bottom brocessed thin film technologies   | 40 |
| Figure 15 – By  | pass diode thermal test   | 41 |
| Table 1 – Pull  | forces for cord anchorage test  | 33 |
| Table 2 – Valu  | es for torsion test   | 33 |
| Table 3 – Ice-b | pall masses and test velocities   | 39 |
| Table 4 – Impa  | act locations   | 39 |

### INTERNATIONAL ELECTROTECHNICAL COMMISSION

# TERRESTRIAL PHOTOVOLTAIC (PV) MODULES - DESIGN QUALIFICATION AND TYPE APPROVAL -

## Part 2: Test procedures

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This first edition of IEC 61215-2 cancels and replaces the second edition of IEC 61215 (2005) and parts of the second edition of 61646 (2008) and constitutes a technical revision.

The main technical changes with regard to these previous editions are as follows:

This standard includes the testing procedures – formally Clause 10 – of the previous edition. Revisions were made to subclauses NMOT (replaces NOCT – MQT 05), performance measurements (MQT 06), robustness of terminations (MQT 14) and stabilization (MQT 19).

The text of this standard is based on the following documents:

| FDIS         | Report on voting |
|--------------|------------------|
| 82/1048/FDIS | 82/1076/RVD      |

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts in the IEC 61215 series, published under the general title *Terrestrial photovoltaic (PV) modules – Design qualification and type approval*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- · replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

# INTRODUCTION

Whereas Part 1 of this standard series describes requirements (both in general and specific with respect to device technology), the sub-parts of Part 1 define technology variations and Part 2 defines a set of test procedures necessary for design qualification and type approval. The test procedures described in Part 2 are valid for all device technologies.

# TERRESTRIAL PHOTOVOLTAIC (PV) MODULES - DESIGN QUALIFICATION AND TYPE APPROVAL -

# Part 2: Test procedures

# 1 Scope and object

This International Standard series lays down IEC requirements for the design qualification and type approval of terrestrial photovoltaic modules suitable for long-term operation in general open-air climates, as defined in IEC 60721-2-1. This part of IEC 61215 is intended to apply to all terrestrial flat plate module materials such as crystalline silicon module types as well as thin-film modules.

This standard does not apply to modules used with concentrated sunlight although it may be utilized for low concentrator modules (1 to 3 suns). For low concentration modules, all tests are performed using the current, voltage and power levels expected at the design concentration.

The objective of this test sequence is to determine the electrical and thermal characteristics of the module and to show, as far as possible within reasonable constraints of cost and time, that the module is capable of withstanding prolonged exposure in general open-air climates. The actual lifetime expectancy of modules so qualified will depend on their design, their environment and the conditions under which they are operated.

# 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050, International Electrotechnical Vocabulary (available at http://www.electropedia.org)

IEC 60068-1, Environmental testing – Part 1: General and guidance

IEC 60068-2-21, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-78, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60721-2-1, Classification of environmental conditions – Part 2-1: Environmental conditions appearing in nature – Temperature and humidity

IEC 60891, Photovoltaic devices – Procedures for temperature and irradiance corrections to measured I-V characteristics

IEC 60904-1, Photovoltaic devices – Part 1: Measurements of photovoltaic current-voltage characteristics

IEC 60904-2, Photovoltaic devices – Part 2: Requirements for photovoltaic reference devices

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IEC 60904-3, Photovoltaic devices – Part 3: Measurement principles for terrestrial photovoltaic (PV) solar devices with reference spectral irradiance data

IEC 60904-7, Photovoltaic devices – Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices

IEC 60904-8, Photovoltaic devices – Part 8: Measurement of spectral responsivity of a photovoltaic (PV) device

IEC 60904-9, Photovoltaic devices - Part 9: Solar simulator performance requirements

IEC 60904-10, Photovoltaic devices – Part 10: Methods of linearity measurement

IEC 61215-1, Terrestrial photovoltaic (PV) modules – Design qualification and type approval – Part 1: Test requirements

IEC TS 61836, Solar photovoltaic energy systems – Terms, definitions and symbols

IEC 61853-2, Photovoltaic (PV) module performance testing and energy rating – Part 2: Spectral response, incidence angle, and module operating temperature measurements<sup>1</sup>

IEC 62790, Junction boxes for photovoltaic modules – Safety requirements and tests

ISO 868, Plastics and ebonite – Determination of indentation hardness by means of a durometer (Shore hardness)

### 3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60050 and IEC TS 61836 apply, as well as the following.

## 3.1

## accuracy <of a measuring instrument>

quality which characterizes the ability of a measuring instrument to provide an indicated value close to a true value of the measurand [≈ VIM 5.18]

Note 1 to entry: This term is used in the "true value" approach.

Note 2 to entry: Accuracy is all the better when the indicated value is closer to the corresponding true value.

[SOURCE: IEC 60050-311:2001, 311-06-08]

### 3.2

### control device

irradiance sensor (such as a reference cell or module) that is used to detect drifts and other problems of the solar sun simulator

# 3.3

## electrically stable power output level

state of the PV module where it will operate under long-term natural sunlight exposure in general open-air climates, as defined in IEC 60721-2-1

<sup>1</sup> To be published.